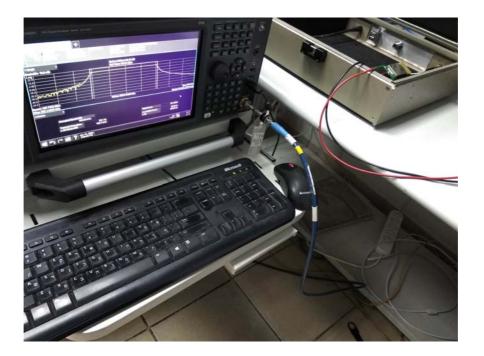


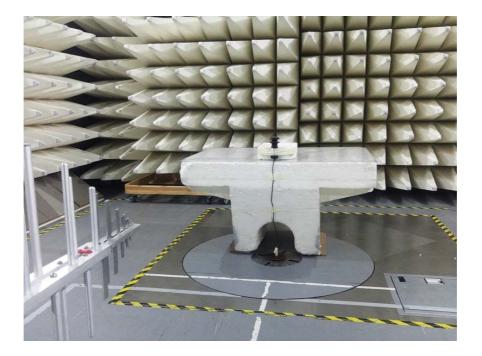
Photograph No.1 Setup for peak output power, hopping parameters, band edge emissions and OBW measurements



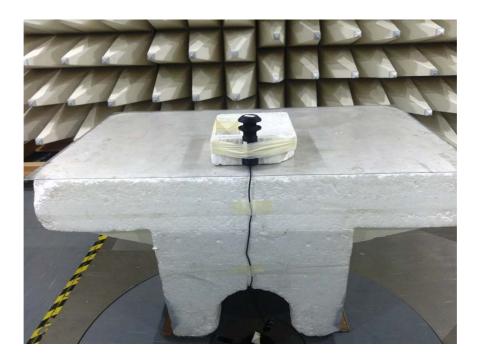
Photograph No.2 Setup for spurious emission measurements in the anechoic chamber below 30 MHz



Photograph No.3 Setup for spurious emissions field strength measurements in the anechoic chamber from 30 to 1000 MHz



Photograph No.4 Setup for spurious emission measurements in the anechoic chamber below 1000 MHz, EUT close view



Photograph No.5 Setup for spurious emission measurements in the anechoic chamber above 1000 MHz

